

April 1988 Revised October 2000

74F673A

16-Bit Serial-In, Serial/Parallel-Out Shift Register

General Description

The 74F673A contains a 16-bit serial-in, serial-out shift register and a 16-bit Parallel-Out storage register. A single pin serves either as an input for serial entry or as a 3-STATE serial output. In the Serial-Out mode, the data recirculates in the shift register. By means of a separate clock, the contents of the shift register are transferred to the storage register for parallel outputting. The contents of the storage register can also be parallel loaded back into the shift register. A HIGH signal on the Chip Select input prevents both shifting and parallel transfer. The storage register may be cleared via STMR.

Features

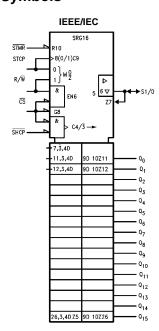
- Serial-to-parallel converter
- 16-bit serial I/O shift register
- 16-bit parallel-out storage register
- Recirculating serial shifting
- Recirculating parallel transfer
- Common serial data I/O pin
- Slim 24 lead package

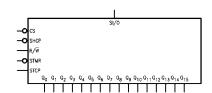
Ordering Code:

| Order Number | Package Number | Package Description |
|--------------|----------------|---|
| 74F673ASC | M24B | 24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide |
| 74F673APC | N24A | 24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-011, 0.600 Wide |
| 74F673ASPC | N24C | 24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0,300 Wide |

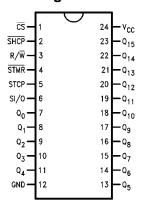
Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbols





Connection Diagram



Unit Loading/Fan Out

| Dia Name | Donasistics. | U.L. | Input I _{IH} /I _{IL} | |
|---------------------------------|---|----------|---|--|
| Pin Names | Description | HIGH/LOW | Output I _{OH} /I _{OL} | |
| CS | Chip Select Input (Active LOW) | 1.0/1.0 | 20 μA/-0.6 mA | |
| SHCP | Shift Clock Pulse Input (Active Falling Edge) | 1.0/1.0 | 20 μA/–0.6 mA | |
| STMR | Store Master Reset Input (Active LOW) | 1.0/1.0 | 20 μA/–0.6 mA | |
| STCP | Store Clock Pulse Input | 1.0/1.0 | 20 μA/–0.6 mA | |
| R/W | Read/Write Input | 1.0/1.0 | 20 μA/–0.6 mA | |
| SI/O | Serial Data Input or | 3.5/1.0 | 70 μA/–0.6 mA | |
| | 3-STATE Serial Output | 150/40 | −3 mA/24 mA | |
| Q ₀ –Q ₁₅ | Parallel Data Outputs | 50/33.3 | −1 mA/20 mA | |

Functional Description

The 16-bit shift register operates in one of four modes, as indicated in the Shift Register Operations Table. A HIGH signal on the Chip Select (CS) input prevents clocking and forces the Serial Input/Output (SI/O) 3-STATE buffer into the high impedance state. During serial shift-out operations, the SI/O buffer is active (i.e., enabled) and the output data is also recirculated back into the shift register. When parallel loading the shift register from the storage register, serial shifting is inhibited.

The storage register has an asynchronous master reset (STMR) input that overrides all other inputs and forces the $\mathrm{Q}_0\mathrm{-Q}_{15}$ outputs LOW. The storage register is in the Hold mode when either $\overline{\text{CS}}$ or the Read/Write (R/ $\overline{\text{W}}$) input is HIGH. With CS and R/W both LOW, the storage register is parallel loaded from the shift register.

Shift Register Operations Table

| Control Inputs | | | ts | SI/O | Operation Meda | | |
|----------------|-----|------|------|----------|--------------------|--|--|
| cs | R/W | SHCP | STCP | Status | Operating Mode | | |
| Н | Х | Х | Х | High Z | Hold | | |
| L | L | | Х | Data In | Serial Load | | |
| L | Н | 7 | L | Data Out | Serial Output | | |
| | | | | | with Recirculation | | |
| L | Н | 7 | Н | Active | Parallel Load; | | |
| | | | | | No Shifting | | |

H = HIGH Voltage Level

Storage Register Operations Table

| Control Inputs | | | | Operating |
|----------------|----|-----|------|--------------------|
| STMR | cs | R/W | STCP | Mode |
| L | Х | Х | Х | Reset; Outputs LOW |
| Н | Н | Х | Х | Hold |
| Н | Х | Н | Х | Hold |
| Н | L | L | ~ | Parallel Load |

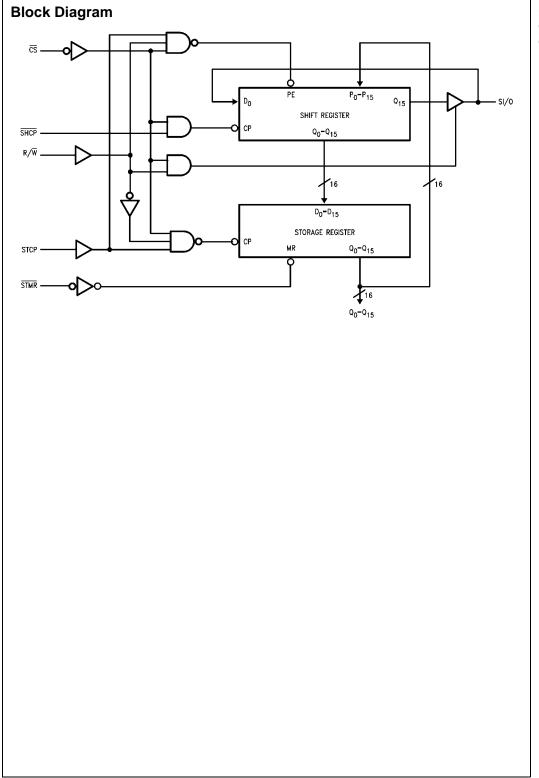
H = HIGH Voltage Level

L = LOW Voltage Level

L = LOW Voltage Level

X = Immaterial

^{∠ =} LOW-to-HIGH Transition



Absolute Maximum Ratings(Note 1)

Storage Temperature -65°C to +150°C -55°C to +125°C

Ambient Temperature under Bias Junction Temperature under Bias $-55^{\circ}C$ to $+150^{\circ}C$ V_{CC} Pin Potential to Ground Pin -0.5V to +7.0V

Input Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) $-30\ mA$ to $+5.0\ mA$

Voltage Applied to Output

in HIGH State (with $V_{CC} = 0V$)

Standard Output -0.5V to V_{CC} 3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA)

Recommended Operating Conditions

Free Air Ambient Temperature 0°C to +70°C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

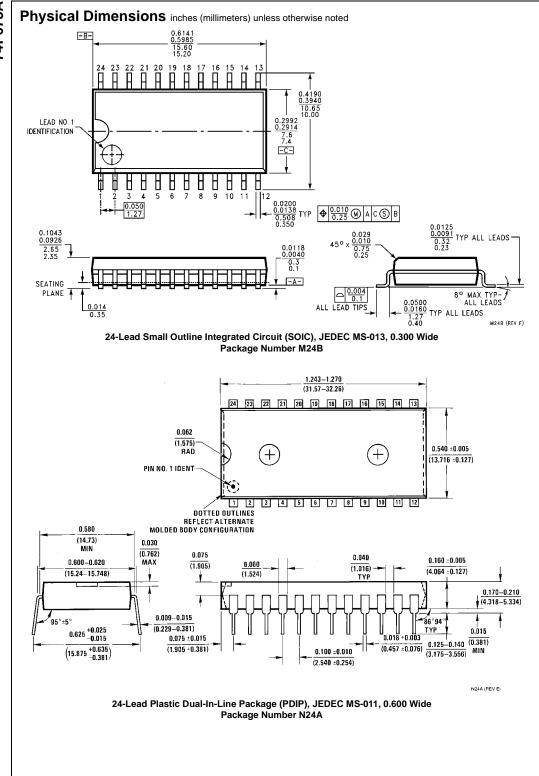
| Symbol | Parameter | 7 | Min | Тур | Max | Units | v _{cc} | Conditions | |
|-------------------|----------------------------|---------------------|-----|--------------------------|------|-------|-----------------|---|--|
| V _{IH} | Input HIGH Voltage | | 2.0 | | | V | | Recognized as a HIGH Signal | |
| V _{IL} | Input LOW Voltage | | | | 0.8 | V | | Recognized as a LOW Signal | |
| V _{CD} | Input Clamp Diode Voltage | е | | | -1.2 | V | Min | I _{IN} = -18 mA (Non I/O pins) | |
| V _{OH} | Output HIGH | 10% V _{CC} | 2.5 | | | | | $I_{OH} = -1 \text{ mA } (Q_n, SI/O)$ | |
| | Voltage | 10% V _{CC} | 2.4 | | | V | Min | $I_{OH} = -3 \text{ mA (SI/O)}$ | |
| | | 5% V _{CC} | 2.7 | | | V | IVIII | $I_{OH} = -1 \text{ mA } (Q_n, SI/O)$ | |
| | | 5% V _{CC} | 2.7 | | | | | $I_{OH} = -3 \text{ mA (SI/O)}$ | |
| V _{OL} | Output LOW | 10% V _{CC} | | | 0.5 | V | Min | $I_{OL} = 20 \text{ mA } (Q_n)$ | |
| | Voltage | 10% V _{CC} | | | 0.5 | V | IVIIII | I _{OL} = 24 mA (SI/O) | |
| I _{IH} | Input HIGH Current | | | | 20 | μΑ | Max | V _{IN} = 2.7V (Non I/O pins) | |
| I _{BVI} | Input HIGH Current | | | | 100 | μА | Max | V _{IN} = 7.0V (Non I/O pins) | |
| | Breakdown Test | | | VIN = 7.0V (NOTHOD PINS) | | | | | |
| I _{BVIT} | Input HIGH Current | | | | 1.0 | mA | Max | V _{IN} = 5.5V (SI/O) | |
| | Breakdown Test (I/O) | | | | 1.0 | IIIA | IVIAX | VIN = 3.3V (3I/O) | |
| I _{IL} | Input LOW Current | | | | -0.6 | mA | Max | V _{IN} = 0.5V | |
| I _{IH} + | Output Leakage | | | | 70 | μА | Max | V _{OLIT} = 2.7V (SI/O) | |
| I _{OZH} | Current | | | | 70 | μΛ | IVIAX | VOUT = 2.7 V (31/0) | |
| I _{IL} + | Output Leakage | | | | -650 | μА | Max | V _{OLIT} = 0.5V (SI/O) | |
| I _{OZL} | Current | | | | -030 | μΛ | IVIAX | VOUT = 0.3V (31/O) | |
| Ios | Output Short-Circuit Curre | ent | -60 | | -150 | mA | Max | V _{OUT} = 0V | |
| I _{CEX} | Output HIGH Leakage Cu | rrent | | | 250 | μΑ | Max | $V_{OUT} = V_{CC}$ | |
| I _{ZZ} | Bus Drainage Test | | | | 500 | μΑ | 0.0V | V _{OUT} = 5.25V | |
| I _{CCH} | Power Supply Current | | | 114 | 172 | mA | Max | V _O = HIGH | |
| I _{CCL} | Power Supply Current | | | 114 | 172 | mA | Max | $V_O = LOW$ | |

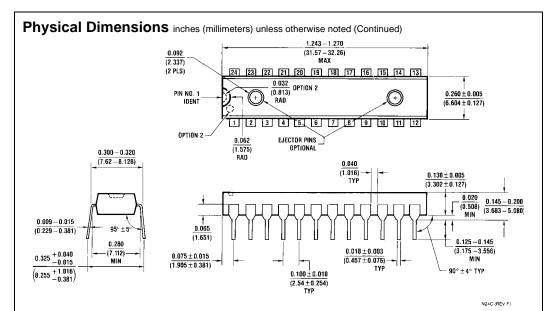
AC Electrical Characteristics

| Symbol | Parameter | $T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$ | | | $T_A = 0$ °C to +70°C $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$ | | Units |
|------------------|-------------------------|---|------|------|--|------|-------|
| | | Min | Тур | Max | Min | Max | |
| f _{MAX} | Maximum Clock Frequency | 100 | 130 | | 85 | | MHz |
| t _{PLH} | Propagation Delay | 3.0 | 8.0 | 10.5 | 2.5 | 12.0 | ns |
| t _{PHL} | STCP to Q _n | 3.0 | 10.5 | 13.5 | 2.5 | 15.0 | 115 |
| t _{PHL} | Propagation Delay | 6.0 | 16.5 | 20.5 | 5.5 | 22.5 | ns |
| | STMR to Q _n | | | | • • • | | |
| t _{PLH} | Propagation Delay | 4.0 | 6.5 | 8.5 | 3.5 | 9.5 | ne |
| t _{PHL} | SHCP to SI/O | 4.5 | 8.0 | 10.5 | 4.0 | 12.0 | ns |
| t _{PZH} | Output Enable Time | 5.0 | 8.5 | 11.0 | 4.0 | 12.5 | |
| t _{PZL} | CS to SI/O | 5.5 | 9.0 | 11.5 | 4.5 | 13.0 | ns |
| t _{PHZ} | Output Disable Time | 3.5 | 5.5 | 7.5 | 3.0 | 8.5 | 115 |
| t _{PLZ} | CS to SI/O | 3.0 | 4.5 | 6.5 | 2.5 | 7.5 | |
| t _{PZH} | Output Enable Time | 4.5 | 7.5 | 9.5 | 4.0 | 10.5 | |
| t _{PZL} | R/W to SI/O | 4.5 | 8.0 | 10.0 | 4.0 | 11.5 | ns |
| t _{PHZ} | Output Disable Time | 3.0 | 5.5 | 7.0 | 2.5 | 8.0 | 113 |
| t _{PLZ} | R/W to SI/O | 2.5 | 4.0 | 5.5 | 2.0 | 6.5 | |

AC Operating Requirements

| | | $T_A = +25$ °C | | $T_A = 0$ °C to +70°C | | |
|--------------------|-------------------------|----------------|------------------|-----------------------|------------------|-----|
| Symbol | Parameter | | $V_{CC} = +5.0V$ | | $V_{CC} = +5.0V$ | |
| | | Min | Max | Min | Max | |
| t _S (H) | Setup Time, HIGH or LOW | 3.5 | | 4.0 | | |
| t _S (L) | CS or R/W to STCP | 6.0 | | 7.0 | | ns |
| t _H (H) | Hold Time, HIGH or LOW | 0 | | 0 | | 113 |
| t _H (L) | CS or R/W to STCP | 0 | | 0 | | |
| t _S (H) | Setup Time, HIGH or LOW | 3.0 | | 3.5 | | |
| t _S (L) | SI/O to SHCP | 3.0 | | 3.5 | | ns |
| t _H (H) | Hold Time, HIGH or LOW | 3.0 | | 3.5 | | 113 |
| t _H (L) | SI/O to SHCP | 3.0 | | 3.5 | | |





24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N24C

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